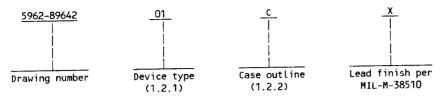
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1. SCOPE

1.1 <u>Scope</u>. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part or Identifying Number (PIN). The complete PIN shall be as shown in the following example:



1.2.1 <u>Device type(s)</u>. The device type(s) shall identify the circuit function as follows:

Device type Generic number Circuit function

O1 AD842 Wideband, high output current, fast settling, operational amplifier

1.2.2 Case outline(s). The case outline(s) shall be as designated in NIL-STD-1835, and as follows:

Outline letter	Descriptive designator	Terminals	Package style
r	GDIP1-T14 or CDIP2-T14	14	Dual-in-line
v	See figure 1	12	Can
2	cqcc1-N2O	20	Square leadless chip carrier

1.3 Absolute maximum ratings. 1/2/

Voltage between V+ and V- terminals - - - - - - - - - - - - 36 V dc Differential input voltage ----- ±6.0 V dc Voltage at either input terminal ----- V+ to V-Storage temperature range - -Power dissipation (P_D) : _____ 1.3 W 3/ Case C - - - - -Case X ----- 1.5 W 3/ Case 2 ----- 1.0 W 3/ Lead temperature (soldering, 10 seconds) -----+300°C Thermal resistance, junction-to-case (Θ_{JC}) : Cases C and X - - - - - - - -Case 2 -----Thermal resistance, junction-to-ambient (Θ_{JA}) : Case C -----Case 2 ----- 150°C/W
Junction temperature (T_J) -----+175°C

1.4 Recommended operating conditions.

2/ Unless otherwise specified, T_A = +25°C . 3/ Derate linearly above T_A = +25°C for case C at 8.7 mW/°C, case X at 10 mW/°C, and case 2 at 6.7 mW/°C.

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^{1/} Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.

2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

 Microcircuits, General Specification for. MIL-M-38510

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.
MIL-STD-1835 - Microcircuit Case Outlines

BULLETIN

MILITARY

- List of Standardized Military Drawings (SMD's). MIL-BUL-103

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

- 3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.
- 3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.
 - 3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.2 herein and figure 1.
 - 3.2.2 <u>Terminal connections</u>. The terminal connections shall be as specified on figure 2.
- 3.3 <u>Electrical performance characteristics</u>. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.
- 3.4 <u>Electrical test requirements</u>. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.
- 3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-BUL-103 (see 6.6 herein).
- 3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD- $\overline{883}$ (see 3.1 herein) and the requirements herein.

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Test	Symbol	Conditions $\underline{1}/$ $-55^{\circ}C \leq T_{\underline{A}} \leq +125^{\circ}C$ $V \pm = \pm 15 V$	Group A	Limits <u>2</u> /		Unit
		V± = ±15 V unless otherwise specified		Min	Max	
Input offset voltage	v _{IO}	v _{CM} = 0 v	11	-1.5	+1.5	_ mV
111put 011voot 111put 0	10	Cn	2,3	-3.5	+3.5	
Input bias current	 +I _B	 v _{CM} = 0 v	11		+8	μΑ
	į B	CH	2,3		+12	Ļ
	-I _B	V _{CM} = 0 V	1	-8		Ĺ
	6	Cn	2,3	-12		
Input offset current	IIIO	V _{CM} = 0 V	11	-0.4	+0.4	μΑ
	10	CIT	2,3	-0.6	+0.6	
Common mode voltage range	 +V _{CM} 	V+ = 5.0 V, V- = -25 V, V _{OUT} = -10 V	1,2,3	 10 		V
	-v _{cm}	V+ = 25 V, V- = -5.0 V,	1,2,3		-10	
Large signal voltage gain	+A _{VOL}	ν _{ουΤ} = 0 v and 10 v, R _L = 500Ω	1 1	40		 V/mV
Large Signat Voltage gain	VOL		2,3	20		
	-A _{VOL}	IV = 0 V and -10 V	1	40		1
	, ~VoL	V _{OUT} = 0 V and -10 V, R _L = 500Ω	2,3	20		
Output current	+I _{OUT}	V _{OUT} = -10 V, T _A = +25°C	1	100		 mA
	^{-I} out	V _{OUT} = +10 V, T _A = +25°C	1		-100	
Output voltage swing	 +V _{OUT}	R _L = 500Ω	1,2,3	10	 	v _
	-v _{out}	R _L = 500Ω	1,2,3		 -10 	<u> </u>
Quiescent power supply	+I _{CC}	V _{OUT} = 0 V, I _{OUT} = 0 mA	1		+14	↓ mA
current		001	2,3	<u> </u>	+19	‡
	-I _{CC}	V _{OUT} = 0 V, I _{OUT} = 0 mA	11	<u> </u> -14	<u> </u>	1
	-66	001	2,3	 -19	1	

See footnotes at end of table.

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Test	 Symbol 	Conditions $\underline{1}/$ -55°C \leq T _A \leq +125°C V± = ±15 V	Group A subgroups	Limits <u>2</u> /		Unit
		V± = ±15 V unless otherwise specified		Min	Max	<u> </u>
Power supply rejection ratio	+PSRR	V+ = 5.0 V to 18 V, V- = -15 V	11	86		∐ dB
			2,3	80		<u> </u>
	 -PSRR	 V- = -5.0 V to -18 V, V+ = +15 V	1	86		1
	İ		2,3	80		<u> </u>
Quiescent power	IP _C	 V _{OUT} = 0 V, I _{OUT} = 0 mA	1		420	mW
consumption $3/$			2,3		570	<u> </u>
Differential input resistance <u>4</u> /	R _{IN}	V _{CM} = 0 V, T _A = +25°C	4	50		 kΩ
Gain bandwidth product <u>4</u> /	GBWP	$V_{OUT} = \pm 100 \text{ mV}, R_L = 500\Omega,$ $f_1 = 100 \text{ kHz}, f_2 = 10 \text{ MHz},$ $T_A = +25^{\circ}\text{C}$	4	50 50		MHz
Full power bandwidth 4/ 5/	FPBW	V _{PK} = 10 V, R _L = 500Ω, T _A = +25°C	4	4.7		 MHz
Closed loop stable gain <u>4</u> /	CLSG	R _L = 500Ω, C _L ≤ 10 pF, T _A = +25°C	4	2		 V/V
Common mode rejection ratio	+CMRR	 Delta V _{CM} = 10 V, V+ = 5.0 V,	4	86		dB
common mode rejection ratio		Delta V _{CM} = 10 V, V+ = 5.0 V, V- = -25 V, V _{OUT} = -10 V	5,6	80		
	-CMRR		4	86		<u> </u>
	-Crikik	Delta V _{CM} = -10 V, V+ = 25 V, V- = -5.0 V, V _{OUT} = 10 V	5,6	80		
Settling time <u>4</u> /	ts	A _V = -2 V/V, 10 V step at 0.1% of the final value, R _L = 500Ω, T _A = +25°C	9		 150 	ns
		$ A_V = -2 \text{ V/V}$, 10 V step to 0.01% of the final value, $ R_1 = 500\Omega$, $ T_A = +25^{\circ}\text{C}$	9		200	

See footnotes at end of table.

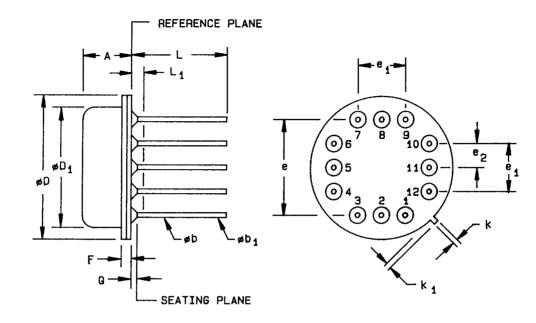
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TABLE I. Electrical performance characteristics.

Test	Symbol Conditions $\underline{1}/$ -55°C \leq T _A \leq +125°C		Group A subgroups	Limits 2/		Unit
		V± = ±15 V unless otherwise specified		Min	Max	<u> </u>
Overshoot 4/	 +0\$ 	$V_{OUT} = 0 \text{ V to } +200 \text{ mV}, A_V +2, \\ R_L = 500\Omega, T_A = +25^{\circ}\text{C}$	9		50	 %
	-os	$V_{OUT} = 0 \text{ V to } -200 \text{ mV}, A_V = +2, R_L = 500\Omega, T_A = +25 ^{\circ}\text{C}$	9	 	50	
Slew rate 4/	+SR	$V_{\text{OUT}} = -5.0 \text{ V to } 5.0 \text{ V, rising edge,}$	4	300	<u> </u>	│ <u>│</u> V/μs
300 Tace 47	İ	$V_{OUT} = -5.0 \text{ V to } 5.0 \text{ V, rising edge,}$ $R_{\parallel} = 500\Omega$, $A_{V} = -2 \text{ V/V, measured from}$ $ 10 \text{ percent to } 90 \text{ percent point}$	5,6	200	ļ	1
	-SR		4	3 <u>00</u>	<u> </u>	
		V_{OUT} = 5.0 V to -5.0 V, falling edge, R_L = 500 Ω , A_V = -2 V/V, measured from 90 percent to 10 percent point	5,6	200	<u> </u>	_
Rise time <u>4</u> / <u>6</u> /	t _R	$V_{OUT} = 0 \text{ V to } +200 \text{ mV}, A_V = +2,$ $R_L = 500\Omega$	9,10,11		10	ns
Fall time <u>4</u> / <u>6</u> /	t _F	$ V_{OUT} = 0 \text{ V to } -200 \text{ mV}, A_V = +2,$ $ R_1 = 500\Omega$	9,10,11		10	ns

- 1/ Unless otherwise specified, for dc tests, R_L = 1000 and V_{OUT} = 0 V.
- 2/ The algebraic convention, whereby the most negative value is a minimum and the most positive is a maximum, is used in this table. Negative current shall be defined as conventional current flow out of a device terminal.
- $\underline{3}$ / Quiescent power consumption is based on quiescent supply current test maximum with no load on outputs.
- 4/ If not tested, shall be guaranteed to the limits specified in table I herein.
- 5/ Full power bandwidth = $\frac{SR}{2 \pi V_{PK}}$.
- $\underline{6}/$ Rise and fall times measured between 10 percent to 90 percent point.
- 3.7 <u>Certificate of conformance</u>. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.
- 3.8 <u>Notification of change</u>. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).
- 3.9 <u>Verification and review</u>. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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Symbol		Inches	Millim	eters	Notes
	Min	Max	Min	Max	
А	0.148	0.181	3.76	4.60	
φb	0.016	0.019	0.41	0.48	1
φ _b ₁	0.016	0.021	0.41	0.53	1
φD	0.592	0.615	15.04	15.62	
<i>Φ</i> D ₁	0.545	0.555	13.84	14.10	
е	0.400 BSC		10.	3	
e ₁	0.200 BSC		5.0	3	
e ₂	0.10	OO BSC	2.5	3	
F		0.040		1.02	
k	0.026	0.036	0.66	0.91	
k ₁	0.027	0.037	0.68	0.94	2
L	0.375		9.50		İ
L ₁		0.050		1.27	1
Q	0.010	0.045	0.25	1.14	

NOTES

- 1. (All leads) ϕ b applies between L and L₁, ϕ b₁ applies between L₁ and 0.375 inch (9.50 mm) from the reference plane. Diameter is uncontrolled in L₁ and beyond 0.375 inch (9.50 mm) from the reference plane.
- Measured from the maximum diameter of the product.
- 3. Leads having a maximum diameter 0.019 inch (0.48 mm) measured in gauging plane 0.054 inch (1.37 mm) + 0.001 inch (0.03 mm) 0.000 inch (0.000 mm) below the base plane of the product are within 0.007 inch (0.18 mm) of their true position relative to the maximum width tab.

FIGURE 1. Case outline X.

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Device type	01			
Case outlines	С	x	2	
Terminal number	Terminal symbol			
1	NC	NC	NC	
2	NC	NC	Balance	
3	Balance	Balance	NC	
4	Input-	 Balance	NC	
5	Input+	 Input-	 Input-	
6	V-	Input+	NC	
7	NC	NC	 Input+	
8	NC	NC NC	NC NC	
9	NC	NC NC	NC NC	
10	Output	V-	V-	
11	 V+	Output	NC NC	
12	NC NC	 V+	NC NC	
13	 Balance		NC NC	
14	NC NC		NC	
15	 		Output	
16			NC NC	
17			 V+	
18			NC NC	
19	i 		NC NC	
 20 	 		Balance	

NC = No connection

FIGURE 2. <u>Terminal connections</u>.

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4. QUALITY ASSURANCE PROVISIONS

- 4.1 <u>Sampling and inspection</u>. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).
- 4.2 <u>Screening</u>. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:
 - a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125$ °C, minimum.
 - b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	1,4
Final electrical test parameters (method 5005)	1*,2,3,4
Group A test requirements (method 5004)	1,2,3,4,5,6, 9**,10**,11**
Groups C and D end-point electrical parameters (method 5005)	1

- * PDA applies to subgroup 1.
- ** Subgroups 9, 10, and 11, if not tested, shall be guaranteed to the limits specified in table I.
- 4.3 <u>Quality conformance inspection</u>. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.
 - 4.3.1 Group A inspection.
 - a. Tests shall be as specified in table II herein.
 - b. Subgroups 5, 6, 7, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.
 - 4.3.2 Groups C and D inspections.
 - a. End-point electrical parameters shall be as specified in table II herein.
 - b. Steady-state life test conditions, method 1005 of MIL-STD-883.
 - (1) Test condition A, B, C, or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125$ °C, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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- 5. PACKAGING
- 5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.
- 6. NOTES
- 6.1 <u>Intended use</u>. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.
- 6.2 <u>Replaceability</u>. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.
- 6.3 <u>Configuration control of SMD's</u>. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).
- 6.4 <u>Record of users</u>. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6021.
- 6.5 <u>Comments</u>. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone (513) 296-5377.
- 6.6 <u>Approved sources of supply</u>. Approved sources of supply are listed in MIL-BUL-103. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS.

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